Saien Xie

List of Publications by Citations

Source: https://exaly.com/author-pdf/3220764/saien-xie-publications-by-citations.pdf

Version: 2024-04-10

This document has been generated based on the publications and citations recorded by exaly.com. For the latest version of this publication list, visit the link given above.

The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

26 26 2,504 12 h-index g-index papers citations 26 4.91 3,033 14.3 avg, IF L-index ext. citations ext. papers

#	Paper	IF	Citations
26	High-mobility three-atom-thick semiconducting films with wafer-scale homogeneity. <i>Nature</i> , 2015 , 520, 656-60	50.4	1224
25	Layer-by-layer assembly of two-dimensional materials into wafer-scale heterostructures. <i>Nature</i> , 2017 , 550, 229-233	50.4	305
24	Electron ptychography of 2D materials to deep sub-figstrfh resolution. <i>Nature</i> , 2018 , 559, 343-349	50.4	269
23	Coherent, atomically thin transition-metal dichalcogenide superlattices with engineered strain. <i>Science</i> , 2018 , 359, 1131-1136	33.3	170
22	Atomically Thin Ohmic Edge Contacts Between Two-Dimensional Materials. ACS Nano, 2016 , 10, 6392-9	16.7	144
21	Heterogeneous integration of single-crystalline complex-oxide membranes. <i>Nature</i> , 2020 , 578, 75-81	50.4	107
20	Long-Lived Hole Spin/Valley Polarization Probed by Kerr Rotation in Monolayer WSe2. <i>Nano Letters</i> , 2016 , 16, 5010-4	11.5	64
19	Tuning Electrical Conductance of MoS Monolayers through Substitutional Doping. <i>Nano Letters</i> , 2020 , 20, 4095-4101	11.5	59
18	Strain Mapping of Two-Dimensional Heterostructures with Subpicometer Precision. <i>Nano Letters</i> , 2018 , 18, 3746-3751	11.5	50
17	Absence of a Band Gap at the Interface of a Metal and Highly Doped Monolayer MoS. <i>Nano Letters</i> , 2017 , 17, 5962-5968	11.5	27
16	Atomic-Scale Spectroscopy of Gated Monolayer MoS2. <i>Nano Letters</i> , 2016 , 16, 3148-54	11.5	23
15	Impact of 2D-3D Heterointerface on Remote Epitaxial Interaction through Graphene. <i>ACS Nano</i> , 2021 , 15, 10587-10596	16.7	15
14	Evidence for the Dominance of Carrier-Induced Band Gap Renormalization over Biexciton Formation in Cryogenic Ultrafast Experiments on MoS Monolayers. <i>Journal of Physical Chemistry Letters</i> , 2020 , 11, 2658-2666	6.4	11
13	Imaging Polarity in Two Dimensional Materials by Breaking Friedel's Law. <i>Ultramicroscopy</i> , 2020 , 215, 113019	3.1	8
12	Utilizing complex oxide substrates to control carrier concentration in large-area monolayer MoS2 films. <i>Applied Physics Letters</i> , 2021 , 118, 093103	3.4	7
11	Strain Accommodation and Coherency in Laterally-Stitched WSe 2 /WS 2 Junctions. <i>Microscopy and Microanalysis</i> , 2016 , 22, 870-871	0.5	5
10	Local Electronic Properties of Coherent Single-Layer WS/WSe Lateral Heterostructures. <i>Nano Letters</i> , 2021 , 21, 2363-2369	11.5	4

LIST OF PUBLICATIONS

9	Interfacial Electron-Phonon Coupling Constants Extracted from Intrinsic Replica Bands in Monolayer FeSe/SrTiO_{3}. <i>Physical Review Letters</i> , 2021 , 127, 016803	7.4	4	
8	Electron Diffraction from a Single Atom and Optimal Signal Detection. <i>Microscopy and Microanalysis</i> , 2016 , 22, 846-847	0.5	3	
7	Resist-Free Lithography for Monolayer Transition Metal Dichalcogenides Nano Letters, 2022,	11.5	3	
6	Breaking Friedel Law in Polar Two Dimensional Materials. <i>Microscopy and Microanalysis</i> , 2017 , 23, 173	8-117539	1	
5	Strong interlayer interactions in bilayer and trilayer moir uperlattices Science Advances, 2022, 8, eab	k1 9 4.3	1	
4	Picometer-Precision Strain Mapping of Two-Dimensional Heterostructures using an Electron Microscope Pixel Array Detector (EMPAD). <i>Microscopy and Microanalysis</i> , 2017 , 23, 1712-1713	0.5		
3	Uncovering Atomic and Nano-scale Deformations in Two-dimensional Lateral Heterojunctions. <i>Microscopy and Microanalysis</i> , 2020 , 26, 1630-1631	0.5		
2	Real-space Demonstration of 0.4 Angstrom Resolution at 80 keV via Electron Ptychography with a High Dynamic Range Pixel Array Detector. <i>Microscopy and Microanalysis</i> , 2018 , 24, 194-195	0.5		
1	Mapping Strain and Relaxation in 2D Heterojunctions with Sub-picometer Precision. <i>Microscopy and Microanalysis</i> , 2018 , 24, 1588-1589	0.5		